氮化鎵快速熱退火處理設備

Technical Information

- ♦ Wafer sizes: Small pieces, 2", 3", 4", 5", 6", 8" wafer capability.
- ♦ Recommended ramp up rate: Programmable, 10°C to 120°C per second.
- ♦ Recommended steady state duration: 0-300 seconds per step.
- ♦ Ramp down rate: Non-programmable, 10°C to 200°C per second..
- Recommended steady state temperature range: 150°C 1000
 °C.
- ♦ ERP Pyrometer 450°C to 1000°C with ±1°C accuracy when calibrated against an instrumented thermocouple wafer.
- → Thermocouple 100-800°C with ±0.5°C accuracy & rapid response.
- → Temperature repeatability: ±0.5°C or better at 1000°C waferto-wafer.
- → Temperature uniformity: ±8°C across an 8"(200mm) wafer at 1000°C. (This is a one sigma deviation 100 angstrom oxide.)

 For a titanium silicide process, no more than 6% increase in 100 angstrom oxide.)

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non-uniformity during the first anneal at 650°C to 700°C.